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_	Application No.	Applicant(s)	
	09/980,754	LERCH ET AL.	
	Examiner	Art Unit	
	Julio J. Maldonado	2823	

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	SEARCHED		
Class	Subclass	Date	Examiner
438	795, 796, 797, 798, 413, 419	3/1/2004	sen
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		Y)
	DATE	EXMR
East (USPAT; USPGPUB) forming with silicon with (nitride or oxynitride) with doped with substrate with thickness	3/1/2004	gen
(forming with silicon with (nitride or oxynitride) with doped with substrate) and thickness with ("2 nm" or "20 angstroms" or	3/1/2004	KIN
"4 nm" or "40 angstroms")	3/1/2004	Jup